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BEAM INTERACTIONS WITH MATERIALS AND ATOMS

Editors: H.H. Andersen and L.E. Rehn

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Scope of NIM-B

Beam Interactions with Materials and Atoms, Section B of Nuclear Instruments and Methods in Physics Research, accepts experimental and theoretical papers of original research covering all aspects of the interaction of energetic beams with atoms, molecules and aggregate forms of matter. This includes ion beam analysis and ion beam modification of materials as well as basic data of importance for these studies.

Topics of general interest include atomic collisions in solids, particle channeling, all aspects of collision cascades, the modification of materials by energetic beams, ion implantation, irradiation-induced changes in materials, the physics and chemistry of ion interactions and the analysis of materials by all forms of energetic radiation. Modification by ion, laser and electron beams for the study of electronic materials, metals, ceramics, insulators, polymers and other important and new material systems are included. Related studies, such as the application of ion beam analysis to biological, archaeological and geological samples, as well as applications to solve problems in planetary science, are also welcome. Energetic beams of interest include atomic and molecular ions, neutrons, positrons and muons, plasmas directed at surfaces, electron and photon beams, including laser treated surfaces and studies of solids by photon radiation from rotating anodes, synchrotrons, etc. In addition, the interaction between various forms of radiation and radiation-induced deposition processes are relevant.

Below are listed keywords to the specialized fields within the scope of the journal.

Basic Data for Materials Modification and Analysis

Range distributions
Stopping powers in gases and solids
X-ray cross sections
Fluorescence yields
Nuclear reaction cross sections
Scattering cross sections

Atomic Collisions in Solids

Atomic and molecular collisions
Collision cascades
Surface interactions
Beam-induced desorption
Beam—foil spectroscopy
Secondary particle emission, sputtering
Channeling
Multiple scattering

Ion Beam Modification of Materials

Ion implantation
Ion beam mixing
Beam-enhanced deposition
Electrical properties of semiconductors
New-phase formation
Optical properties
Defect properties
Friction, wear, erosion
Interfaces, adhesion
Oxidation and corrosion
Superconductivity
Magnetic properties
Other property changes

Effects of Radiation

Radiation damage
Particle tracks
Cluster beams
Interaction of plasmas
Laser ablation
Laser and electron-beam induced modification
Energy and radiation transport in matter
High-intensity beams
Other directed energy processes

Analysis of Materials

Ion beam analysis
Ion channeling
Ion backscattering
Elastic recoil detection
Ion-induced X-rays
Ion-induced nuclear reactions
Low energy ion beam analysis
Secondary ion mass spectroscopy
Secondary electron spectroscopy
Neutron scattering
Slow positron beams
Subatomic particle analyses
Mössbauer spectroscopy
Photon beams
X-ray techniques
Accelerator mass spectroscopy
Nuclear dating techniques

Ion Sources and Beam Optics

Sputter sources
ECR sources
Microbeam sources
Other ion sources
Beam optics for analysis and collision studies
Microprobes

Experimental Methods and Equipment

Dosimetry
Target-temperature regulation systems
High-intensity beams
Beam scanning systems
Fitting and interpretation of energy spectra
New experimental methods
New instrumentation concepts

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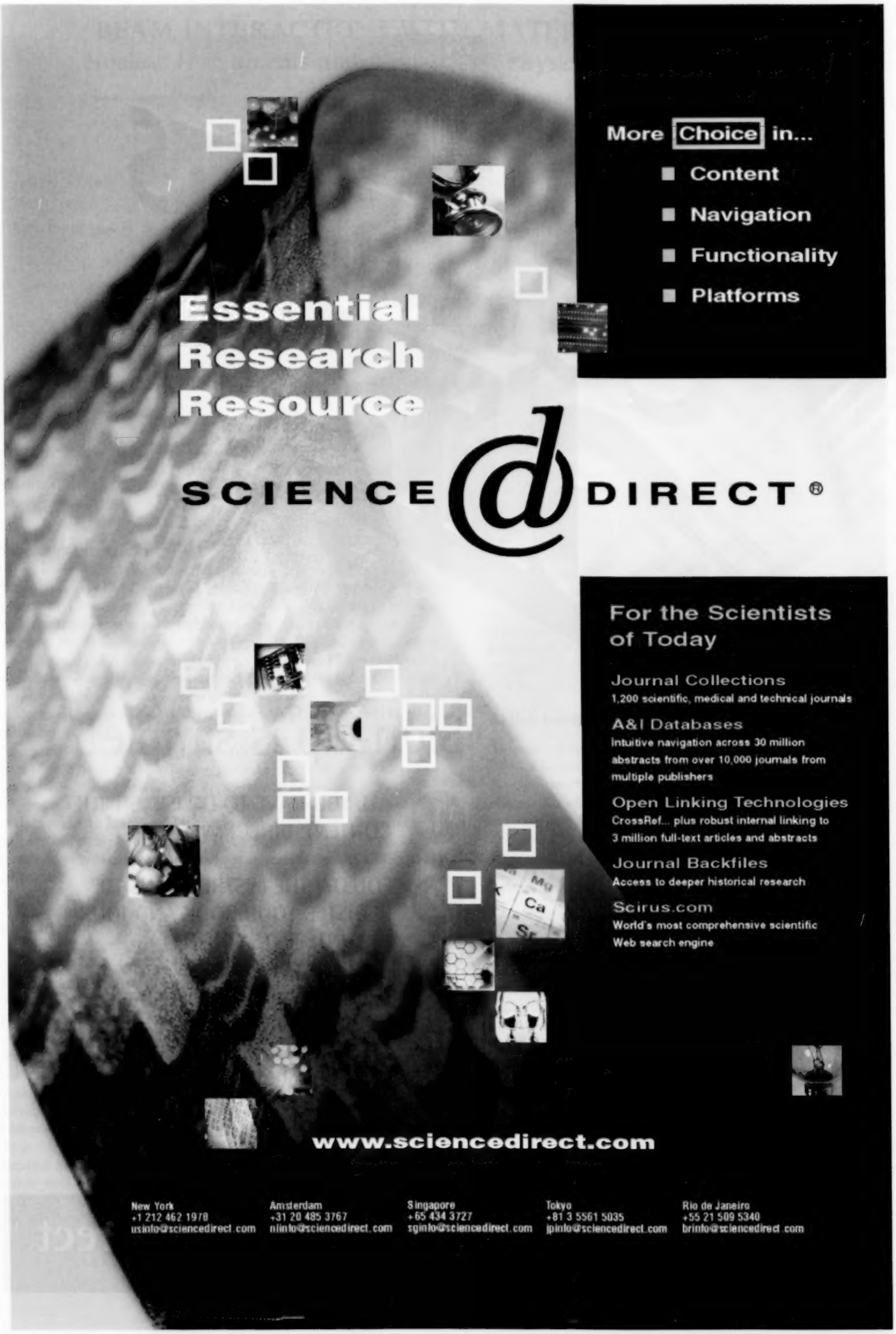
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